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For each	That	You must determine
1. Wet-out area	Is uncontrolled	Annual uncontrolled wet-out area organic HAP emissions.
2. Wet-out area	a. Has an enclosure that is not a PTE	The capture efficiency of the enclosure, and Annual organic HAP emissions that escape the enclosure.
3. Wet-out area	Has an enclosure that is a PTE	That the enclosure meets the require- ments of EPA Method 204 of appendix M to 40 CFR part 51 for a PTE.
4. Oven	Is uncontrolled	Annual uncontrolled oven organic HAP emissions.
5. Line	a. Is controlled or uncontrolled	The amount of neat resin plus applied, and The amount of neat gel coat plus applied.
6. Add-on control device		i. Total annual inlet organic HAP emissions, and total annual outlet organic HAP emissions.

TABLE 12 TO SUBPART WWWW OF PART 63—DATA REQUIREMENTS FOR NEW AND EXISTING CONTINUOUS LAMINATION LINES AND CONTINUOUS CASTING LINES COMPLYING WITH A LBS/TON ORGANIC HAP EMISSIONS LIMIT ON A PER LINE BASIS

As required in $\S63.5865(b)$, in order to comply with a lbs/ton organic HAP emissions limit for continuous lamination lines and continuous casting lines you must determine the data in the following table:

For each line where the wet- out area	And the oven	You must determine
1. Is uncontrolled	a. Is uncontrolled	i. Annual uncontrolled wet-out area organic HAP emissions, ii. Annual uncontrolled oven organic HAP emissions, and iii. Annual neat resin plus and neat gel coat plus applied.
Has an enclosure that is not a PTE and the captured organic HAP emis- sions are controlled by an add-on con- trol device.	a. Is uncontrolled	i. Annual uncontrolled wet-out area organic HAP emissions, ii. Annual controlled wet-out area organic HAP emissions, iii. Annual uncontrolled oven organic HAP emissions.
Has an enclosure that is a PTE, and the captured organic HAP emissions are controlled by an add-on control device.	a. Is uncontrolled	iv. The capture efficiency of the wet-out area enclosure, v. The destruction efficiency of the add-on control device, and vi. The amount of neat resin plus and neat gel coat plus applied. i. Annual uncontrolled wet-out area organic HAP emissions, iii. Annual controlled wet-out area organic HAP emissions, iii. Annual uncontrolled oven organic HAP emissions, iv. That the wet-out area enclosure meets the requirements of EPA Method 204 of appendix M to 40 CFR part
4. Is uncontrolled	a. Is controlled by an add-on control device.	od 204 of appendix with 40 CPR part 51 for a PTE, v. The destruction efficiency of the add- on control device, and vi. The amount of neat resin plus and neat gel coat plus applied. i. Annual uncontrolled wet-out area or- ganic HAP emissions, ii. Annual uncontrolled oven organic HAP emissions, iii. Annual controlled oven organic HAP emissions,

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For each line where the wet- out area	And the oven	You must determine
 Has an enclosure that is not a PTE and the captured organic HAP emis- sions are controlled by an add-on con- trol device. 	a. Is controlled by an add-on control device.	iv. The capture efficiency of the oven, v. The destruction efficiency of the add- on control device, and vi. The amount of neat resin plus and neat gel coat plus applied. i. Annual uncontrolled wet-out area or- ganic HAP emissions, iii. Annual uncontrolled oven organic HAP emissions, iv. Annual controlled oven organic
Has an enclosure that is a PTE, and the captured organic HAP emissions are controlled by add-on control device.	a. Is controlled by an add-on control device.	emissions, v. The capture efficiency of the wet-out area enclosure, vi. The capture efficiency of the oven, vii. The destruction efficiency of the add-on control device, and viii. The amount of neat resin plus and neat gel coat plus applied. i. That the wet-out area enclosure meets the requirements of EPA Method 204 of appendix M to 40 CFR part 51 for a PTE, ii. The capture efficiency of the oven, iii. Inlet organic HAP emissions to the an add-on control device, and iv. Outlet organic HAP emissions from the add-on control device.

Table 13 to Subpart WWWW of Part 63—Applicability and Timing of Notifications

As required in $\S63.5905(a)$, you must determine the applicable notifications and submit them by the dates shown in the following table:

If your facility	You must submit	By this date
1. Is an existing source subject to this subpart.	An Initial Notification containing the information specified in § 63.9(b)(2).	No later than the dates specified in § 63.9(b)(2).
2. Is a new source subject to this subpart	The notifications specified in § 63.9(b)(4) and (5).	No later than the dates specified § 63.9(b)(4) and (5).
3. Qualifies for a compliance extension as specified in § 63.9(c).	A request for a compliance extension as specified in § 63.9(c).	No later than the dates specified in § 63.6(i).
4. Is complying with organic HAP emissions limit averaging provisions.	A Notification of Compliance Status as specified in § 63.9(h).	No later than 1 year plus 30 days after your facility's compliance date.
 Is complying with organic HAP content limits, application equipment require- ments, or organic HAP emissions limit other than organic HAP emissions limit averaging. 	specified in §63.9(h).	No later than 30 calendar days after your facility's compliance date.
Is complying by using an add-on control device.	a. A notification of intent to conduct a performance test as specified in § 63.9(e).	No later than the date specified in § 63.9(e).
	b. A notification of the date for the CMS performance evaluation as specified in § 63.9(g).	The date of submission of notification of intent to conduct a performance test.
	c. A Notification of Compliance Status as specified in § 63.9(h).	No later than 60 calendar days after the completion of the add-on control device performance test and CMS performance evaluation.

Table 14 to Subpart WWWW of Part 63—Requirements for Reports

As required in 63.5910(a), (b), (g), and (h), you must submit reports on the schedule shown in the following table: